

Notice of References Cited	Application/Control No. 10/798,157	Applicant(s)/Patent Under Reexamination LI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	✓ JP 2000-63433	02-2000	Japan	Iwasa et al.	N/A
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	✓ Chemical Abstract (132:187644) for JP 2000-63433 (Iwasa et al).
	V	✓ Machine-assisted English translation for JP 2000-63433 (Iwasa et al) provided by JPO.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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